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APPLICANTS: _Harari et al_

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THE UNDERSIGNED HEREBY RESPECTFULLY REQUESTS ACCESS TO THE FILE HISTORY OF THE FOLLOWING ABANDONED APPLICATION WHICH WAS REFERRED TO IN U.S. PATENT NUMBER _5297148_ OR PRINTED APPLICATION _____.

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United States Patent [19]

Harari et al.

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[45] Date of Patent: **Mar. 22, 1994**

US005297148A

[54] **FLASH EEPROM SYSTEM**

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[73] Assignee: **SunDisk Corporation**, Santa Clara, Calif.

[21] Appl. No.: **963,838**

[22] Filed: **Oct. 20, 1992**

Related U.S. Application Data

[62] Division of Ser. No. 337,566, Apr. 13, 1989, abandoned.

[51] Int. Cl.^{5} **G06F 11/00**
[52] U.S. Cl. **371/10.2**; 371/10.1; 371/10.3; 365/200
[58] Field of Search 371/10.2, 10.1, 10.3, 371/40.1; 365/200

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[57] **ABSTRACT**

A system of Flash EEprom memory chips with controlling circuits serves as non-volatile memory such as that provided by magnetic disk drives. Improvements include selective multiple sector erase, in which any combinations of Flash sectors may be erased together. Selective sectors among the selected combination may also be de-selected during the erase operation. Another improvement is the ability to remap and replace defective cells with substitute cells. The remapping is performed automatically as soon as a defective cell is detected. When the number of defects in a Flash sector becomes large, the whole sector is remapped. Yet another improvement is the use of a write cache to reduce the number of writes to the Flash EEprom memory, thereby minimizing the stress to the device from undergoing too many write/erase cycling.

4 Claims, 5 Drawing Sheets